Docket No.: 3449-0567PUS1

## **AMENDMENTS TO THE CLAIMS**

1-32. (Cancelled)

33. (Currently Amended) A light emitting diode (LED) comprising:

a first gallium nitride layer;

an In<sub>x</sub>Ga<sub>1-x</sub>N/In<sub>y</sub>Ga<sub>1-y</sub>N multi-layer formed over the first gallium nitride layer;

an active layer formed over the In<sub>x</sub>Ga<sub>1-x</sub>N/In<sub>y</sub>Ga<sub>1-y</sub>N multi-layer; and

a second gallium nitride layer formed over the active layer,

wherein the In<sub>x</sub>Ga<sub>1-x</sub>N/In<sub>y</sub>Ga<sub>1-y</sub>N multi-layer has a plurality of pits formed thereon.

34. (Previously Presented) The LED according to claim 33, wherein the active layer comprises an InGaN/InGaN structure of a multi-quantum well structure.

35. (Cancelled)

- 36. (Currently Amended) The LED according to claim 35 claim 33, wherein the number of the pits is 50 or less per area of 5μm×5μm.
- 37. (Previously Presented) The LED according to claim 33, wherein the  $In_xGa_{1-x}N/In_yGa_{1-y}N$  multi-layer is formed to have a super lattice structure.

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38. (Previously Presented) The LED according to claim 33, wherein each layer of the

In<sub>x</sub>Ga<sub>1-x</sub>N/In<sub>y</sub>Ga<sub>1-y</sub>N multi-layer has a thickness of 1~3000 Å.

39. (Previously Presented) The LED according to claim 33, wherein the In<sub>x</sub>Ga<sub>1</sub>.

<sub>x</sub>N/In<sub>y</sub>Ga<sub>1-y</sub>N multi-layer has a photoluminescence characteristic of a yellow band intensity/N-

doped GaN intensity ratio of 0.4 or below.

40. (Previously Presented) The LED according to claim 33, wherein the active layer is

directly formed on the In<sub>x</sub>Ga<sub>1-x</sub>N/In<sub>y</sub>Ga<sub>1-y</sub>N multi-layer

41. (Previously Presented) The LED according to claim 33, wherein the LED is blue

LED.

42. (Currently Amended) A method for manufacturing a light emitting device, the

method comprising the steps of:

forming an N-type gallium nitride layer;

forming an In<sub>x</sub>Ga<sub>1-x</sub>N/In<sub>y</sub>Ga<sub>1-y</sub>N multi-layer above the N-type gallium nitride layer, the

In<sub>x</sub>Ga<sub>1-x</sub>N/In<sub>y</sub>Ga<sub>1-y</sub>N multi-layer including layers of first and second growth temperatures;

forming an active layer above the In<sub>x</sub>Ga<sub>1-x</sub>N/In<sub>y</sub>Ga<sub>1-y</sub>N multi-layer; and

forming a P-type gallium nitride layer above the active layer,

wherein the active layer is grown at a temperature lower than the first and second

temperatures, and

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wherein the In<sub>x</sub>Ga<sub>1-x</sub>N/In<sub>y</sub>Ga<sub>1-y</sub>N multi-layer has a plurality of pits formed thereon.

43. (Previously Presented) The method according to claim 42, wherein the active layer is

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grown at 600~800 °C.

44. (Previously Presented) The method according to claim 42, wherein the active layer

comprises an InGaN/InGaN structure of a multi-quantum well structure.

45. (Cancelled)

46. (Currently Amended) The method according to claim 45 claim 42, wherein the

number of the pits is 50 or less per area of 5µm×5µm.

47. (Previously Presented) The method according to claim 42, wherein the In<sub>x</sub>Ga<sub>1</sub>.

<sub>x</sub>N/In<sub>v</sub>Ga<sub>1-v</sub>N multi-layer is formed to have a super lattice structure.

48. (Previously Presented) The method according to claim 42, wherein each layer of the

In<sub>x</sub>Ga<sub>1-x</sub>N/In<sub>y</sub>Ga<sub>1-y</sub>N multi-layer has a thickness of 1~3000 Å.

49. (Previously Presented) The method according to claim 42, wherein the In<sub>x</sub>Ga<sub>1</sub>.

<sub>x</sub>N/In<sub>y</sub>Ga<sub>1-y</sub>N multi-layer has a photoluminescence characteristic of a yellow band intensity/N-

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doped GaN intensity ratio of 0.4 or below.

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50. (Previously Presented) The method according to claim 42, wherein the active layer is directly formed on the  $In_xGa_{1-x}N/In_yGa_{1-y}N$  multi-layer.